<u>Standard specifications of</u> 10×15 mm² β-Ga₂O₃ epitaxial wafer (by MBE)

Epitaxial layer

Items	Specifications		β-Ga ₂ O ₃ epitaxial layer
Dopant	Si (n-type)	Undoped (semi-insulating)	β -Ga ₂ O ₃ wafer
Doping concentration *A value can be selected within the described range.	Specify a value in the range between 1×10 ¹⁷ and 2×10 ¹⁸ cm ⁻³	-	Cross section of β -Ga ₂ O ₃ epitaxial wafer
Thickness *A value can be selected within the described range.	Specify a value in the range between 0.1 and 0.5 µm		
Wafer			
Items	Specifications		
Dopant	Sn (n-type)	Fe (semi-insulating)	(010)
Doping concentration	Using the range of 1-9×10 ¹⁸ cm ⁻³	-	(010)
Resistivity	-	≧10 ¹⁰ Ωcm	
Orientation	(010)		[001] 53.8
Size	10×15 mm ²		[::::::::::::::::::::::::::::::::::::::
Thickness	0.5 mm		Orientation
XRD FWHM	≤150 arcsec		
Off set angle	0°±1°		
Deveender			

Remarks

 $\ensuremath{\mathbf{1}}$ These products must be used for research and development purposes only.

2 The substrates must not be used as a seed crystal.

3 The specifications are subject to change without notice.

Novel Crystal Technology, Inc. 2024.7.31